White Paper

Trigger synchronization and phase coherent in high speed multi-channels data acquisition system

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over multiple Data Acquisition Systems (DAQ) is critical to applications such as radar, electronic warfare and high

Synopsis

applications such as radar, electronic warfare and high energy physics. The latest GSPS ADCs, with sub-nanosecond acquisition period, make the trigger synchronization and phase alignment of multiple acquisition AMCs very challenging to achieve.

Trigger synchronization and phase coherent acquisition

During the integration many factors can influence the synchronization of multi-channel acquisition system. These factors can be external to the digitizer platform such as the length of cables, or internal such as the backplane and PCB trace routing. It is thus necessary for the integrator to know the phase jitter they can expect from a platform and to be able to re-establish a synchronization after integration with external elements.

VadaTech Data Acquisition DAQ Series[™] product line has been enhanced to answer this challenge, and make high density synchronized acquisition at very high speed a reality.

In the following document, we demonstrate the synchronization of two very high speed DAQ AMCs, with an accuracy of up to +- 0.5ps.

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1 Acquisition system architecture

The acquisition system is composed of the following items:

- VT866 chassis (5U, PCIe gen3 capable, 12 slots chassis)
- UTC002 MCH
- AMC004 Reference clock / Trigger generator
- AMC516 FMC225 (1 channel 4GSPS ADC)
- AMC517 FMC226 (2 channels 4GSPS ADC)
- AMC725 running VadaTech DAQ Series™ Input Output Controller (IOC)
- Remote computer running VadaTech DAQ Series™ Graphical User Interface

Deterministic synchronized acquisition requires a common reference clock, as well as a fixed phase difference between the trigger signal and the reference clock. These requirements are met by using the AMC004 as a reference clock / trigger generator, with the clock routing capabilities of the VT866 chassis and the UTC002 MCH.

The AMC004's 10MHz reference clock is routed to the backplane TCLKA. The UTC002 clock Cross Bar Switch routes this reference clock to the AMC516 and AMC517 TCLKA.

The Acquisition input signal is distributed to the FMC225/FMC226 via a RF splitter, and length-matched cables (to give phase alignment of the two input signals).



Figure 1: Synchronized DAQ Architecture

The AMC004's time trigger function generates a trigger event at a given GPS time. This trigger signal has a deterministic phase



Figure 2: Deterministic delay between AMC004 trigger and 10MHz clock

relationship to the 10MHz reference clock. The trigger generator is controlled over PCIe by the DAQ IOC running on the AMC725. The trigger signal is routed from the AMC004 front panel (CLK OUT) to the FMC225/FMC226 front panel (TRIG IN). The cable lengths between the trigger splitter and the FMC225/FMC226 TRIG IN are the same length.



Figure 3: ADC12J4000 Digital Down Converter

The ADCs (ADC 12J4000) on FMC225/FMC226 are configured with a 4x Digital Down Converter (DDC). The ADC's internal Direct Digital Synthesizer (DDS) center frequency can be configured from the DAQ Series[™] GUI. The ADC output is a 15bit I/Q, 1GHz bandwidth DC-centered signal, transferred to the FPGA via the JESD204B protocol.

Two instances of the DAQ Series[™] IOC run in parallel on the AMC725, each providing the control/status/results interface to its respective DAQ AMC over PCIe.

The DAQ Graphical User Interface has been customized to be connected to both DAQ Series IOC, over the AMC725 front panel



Figure 4: DAQ Series dual channel GUI

GbE. The main interface displays the Control and Status of AMC517-FMC226 and AMC516-FMC225. The Amplitude graph displays the I/Q of the current snapshot captured by AMC517-FMC226 and AMC516-FMC225, as well as the snapshot timestamp.

A phase computation is available on the DAQ Series[™] IOC, linked to two types of phase plots in the DAQ Series[™] GUI (Phase and Phase error). This allows the user to monitor the phase difference between AMC516-FMC225 and AMC517-FMC226 in real time.

6

The Phase figure displays the angle (in milli-radian) of the current snapshot captured by AMC517-FMC226 and AMC516-FMC225.

The Phase error figure displays, for each sample (t) of the current snapshot, a point with the coordinates {X = phase of sample (t) AMC516-FMC225, Y = phase of sample (t) AMC517-FMC226}. This plot provides a representation of the phase difference, as well as phase difference jitter.



Figure 5: DAQ Series Phase display

2 Synchronization results

The phase difference (Delta Phase) between AMC516-FMC225 and AMC517-FMC226 has been measured for different input frequencies, and different DDC configurations. The phase difference is then converted to a sampling time difference (Delta sample).

| DDC Center Frequency (MHz) | Input Frequency (MHz) | Delta Phase (mrad) | Delta Sample (ps) |
|-------------------------------|--------------------------|-----------------------|-------------------|
| 1500 | 1302 | 184 | 22.5 |
| 1500 | 1502 | 183 | 19.4 |
| 1500 | 1802 | 101 | 8.9 |
| 2500 | 2302 | -65 | -4.5 |
| 2500 | 2502 | 71 | 4.5 |
| 2500 | 2800 | 44 | 2.5 |
| 3500 | 3302 | -38 | -1.8 |
| 3500 | 3502 | - 11 | -0.5 |
| 3500 | 3802 | 13 | 0.5 |



Figure 6: Result Delta sample vs Frequency

3 Clock architecture

FMC225 and FMC226 are built around the same ADC (TI ADC12J4000) and architecture.

The LMK04828 Dual Loop PLL generates the JESD204B clocks for the FPGA (glblclk, sysref), the JESD204B clock for the ADC (sysref), and the reference clock for the HMC835 PLL.

The HMC835 PLL generates the 4GHz ADC sampling clock (devclk).

The SYNC signal of HMC835 and the ADC12J4000 ADC are driven by the FPGA. The front panel trigger signal has a direct connection to the FPGA (sampled in the FPGA by the glblclk clock).

The ADC 12J4000 serial outputs follow the JESD204B Subclass 1 standard. This standard features a deterministic latency between the ADC and the FPGA via the sysref signals.



Figure 7: FMC225/FMC226 architecture

4 Synchronization acquisition

4.1 PLL configuration

The first step for deterministic synchronized acquisition is to generate all the clocks with a deterministic phase relative to the reference clock (10MHz from AMC004). As the reference clock of both acquisition systems (AMC516-FMC225 and AMC517-FMC226) comes from the same source (AMC004), all the clocks of both systems then have a deterministic phase relation.



Figure 8: System wide clocks relationship

4.2 Deterministic sampling of TRIGGER and JESD204B frame pulse

Some control signals (input trigger, ADC sysref, FPGA sysref) are analog signals, sampled by digital clocks. It is critical to optimize the phase relationship between these signals and their respective capture clock, in order to have deterministic sampling across the DAQ AMCs. As all these signals have a deterministic phase relationship to the reference clock, it is possible to optimize the arrival window relative to their sampling clock.





4.3 Phase calibration

The final step is to adjust the phase relations between both acquisition systems until the required synchronization level is achieved.



Figure 10: System phases relationships

5 PLL configuration

5.1 LMK04828

The LMK04828 is configured in Nested O-delay Dual Loop Mode. In this mode, the feedback to the first PLL (Feedback PLL1) is driven by an output clock (sysref). This causes sysref to have a deterministic phase relationship to the input clock. As a result, all output clocks have a deterministic phase to the input clock. An analog delay with a resolution of 150ps is available on the FPGA and ADC sysref path.



Figure 11: LMK04828 Nested O-delay Dual Loop mode

5.2 HMC835

The HMC835 is configured in Exact Frequency mode. In this mode, the output clock has a deterministic phase relationship with the input clock. The external SYNC signal allows us to finely tune the phase of the output clock relative to the input clock (CLKIN).

The SYNC signal forces the HMC835 to initialize the phase of the output clock relative to the input clock at a user defined value.



Figure 12: HMC835 Exact Frequency Mode

6 Deterministic sampling of TRIGGER and JESD204B frame pulse

The sysref signal is used in JESD204B Subclass 1 as a synchronization signal. This signal is sampled by the 4GHz sampling clock on the ADC side (devclk), and the 250MHz glblclk clock on the FPGA side. Both the ADC and the FPGA implement an analog delay with a "dirty bit detection" engine, which allows the user to optimize the sampling window by tuning the analog delay. As sysref, glblclk, devclk all have a deterministic phase relationship, this adjustment only need to be done once.

The trigger signal is used to synchronize the initial SYNC of the HMC835, the SYNC of the ADC (DDC reset), as well as the start of acquisition. The trigger signal is sampled by the glblclk clock. The FPGA also implements an analog delay coupled with a "dirty bit detection" engine on the trigger path. As the trigger signal has a deterministic phase relationship to the reference clock, it is possible to optimize the sampling window once (by fine tuning the analog delay).

The ADC allows adjustment in the optimal arrival window by steps of 20ps controlled over temperature drift. The FPGA allows adjustment in the optimal arrival window by steps of 78ps controlled over temperature drift.

7 Phase calibration

7.1 FPGA TRIGGER and SYSREF

The trigger signal has to be sampled by both acquisition systems at the same glblclk clock cycle relative to the sampled FPGA sysref signal. This adjustment is done using digital delays in the acquisition system, combined with the ADC configured in test mode (ramp generator).

In test mode, the ADC generates a known sequence of data. This sequence is initialized at the first sysref event following the deassertion of the SYNC signal. If the sequences captured on AMC516-FMC225 and AMC517-FMC226 match, this indicates that the ADC SYNC signal is synchronized on both systems, and that the trigger rising event is sampled at the same time (relative to sysref).

Before adjustment, the ADC test pattern is not synchronized between AMC516-FMC225 and AMC517-FMC226. By monitoring the sampled trigger signal on an oscilloscope, we measure a one glblclk (4ns) clock period between both trigger.



Figure 13: ADC Test Mode, before adjustment



Figure 14: Sampled trigger signal before adjustment

After adjustment, the ADC test pattern is synchronized, and the delay measured between both trigger signals is less than a glblclk clock period (4ns).



Figure 15: ADC Test mode, after adjustment



Figure 16: Sampled trigger signal after adjustment

7.2 ADC SYSREF and DEVCLK

After the tuning of the FPGA's sysref and trigger signal, the final adjustment concerns the ADC sysref and devclk.

The ADC sysref signal has to be sampled on the same devclk clock cycle on both acquisition systems. The ADC sysref signal can be adjusted using the output analog delay in the LMK04828. After adjustment, the acquisition should be synchronized at +-0.5 Acquisition clock cycle (+-125ps). This fine tuning has to be done once.

Finally, the relative phase of both ADCs Acquisition clock (devclk) can be fine-tuned using the HMC835.

The following are the results obtained at the different steps of adjustment.

Before adjustment, the phase difference of a 2502MHz input signal, between AMC516-FMC225 and AMC517-FMC226 is -3 radian.



Figure 17: Measured phase before adjustment



Figure 18: Phase error before adjustment



Figure 19: Input phase after sysref adjustment



Figure 20: Phase error after sysref adjustment

Finally, the fine tuning of the ADC Sampling clock (devclk) phase decreases the phase error up to around 0 radian phase error:



Figure 21: Input phase after ADC Sampling clock adjustment



Figure 22: Phase error after ADC Sampling clock adjustment

8 Annex

8.1 Result DDC at 2500MHz, input 2502MHz



Figure 23: Amplitude DDC 2500MHz, input 2502MHz



Figure 24: Phase DDC 2500MHz, input 2502MHz



Figure 25: Phase error DDC 2500MHz, input 2502MHz

8.2 Result DDC at 2500MHz, input 2800MHz



Figure 26: Amplitude DDC 2500MHz, input 2800MHz



Figure 27: Phase DDC 2500MHz, input 2800MHz



Figure 28: Phase error DDC 2500MHz, input 2800MHz

8.3 Result DDC at 2500MHz, input 2302MHz



Figure 29: Amplitude DDC 2500MHz, input 2302MHz



Figure 30: Phase DDC 2500MHz, input 2302MHz



Figure 31: Phase error DDC 2500MHz, input 2302MHz

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